ESD Protection Diode

Low Clamping Voltage

The NUP4114 ESD protection diode array is designed to protect high speed data lines from ESD. Ultra-low capacitance and high level of ESD protection make these devices well suited for use in USB 2.0 high speed applications.

Features

- Low Clamping Voltage
- Low Capacitance (<0.6 pF Typical, I/O to GND)
- Low Leakage
- Response Time is Typically < 1.0 ns
- IEC61000-4-2 Level 4 ESD Protection
- SZ Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Typical Applications

- LVDS
- USB 2.0 High Speed Data Line and Power Line Protection
- Digital Video Interface (DVI) and HDMI
- Gigabit Ethernet
- Monitors and Flat Panel Displays
- Notebook Computers

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Operating Junction Temperature Range	T_{J}	-40 to +125	°C
Storage Temperature Range	T _{stg}	-55 to +150	°C
Lead Solder Temperature – Maximum (10 Seconds)	TL	260	°C
IEC 61000-4-2 Contact IEC 61000-4-2 Air ISO 10605 330 pF / 330 Ω Contact ISO 10605 330 pF / 2 kΩ Contact ISO 10605 150 pF / 2 kΩ Contact	ESD	±8 ±15 ±10 ±21 ±30	kV

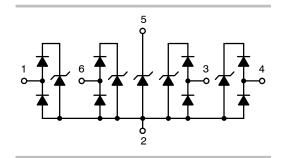
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

See Application Note <u>AND8308/D</u> for further description of survivability specs.



ON Semiconductor®

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MARKING DIAGRAMS



SC-88 W1 SUFFIX CASE 419B





SC-88 W1 SUFFIX CASE 419B





TSOP-6 CASE 318G STYLE 12





SOT-563 CASE 463A



XXX = Specific Device Code

M = Date Code

= Pb-Free Package

(Note: Microdot may be in either location)

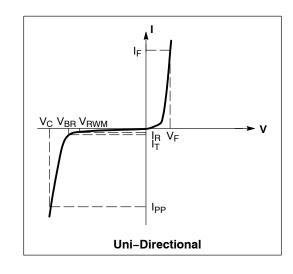
ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 4 of this data sheet.

ELECTRICAL CHARACTERISTICS

(T_A = 25°C unless otherwise noted)

١ ٨	<u>'</u>
Symbol	Parameter
I _{PP}	Maximum Reverse Peak Pulse Current
V _C	Clamping Voltage @ IPP
V_{RWM}	Working Peak Reverse Voltage
I _R	Maximum Reverse Leakage Current @ V _{RWM}
V_{BR}	Breakdown Voltage @ I _T
Ι _Τ	Test Current
I _F	Forward Current
V _F	Forward Voltage @ I _F
P _{pk}	Peak Power Dissipation
С	Capacitance @ V _R = 0 and f = 1.0 MHz



^{*}See Application Note AND8308/D for detailed explanations of datasheet parameters.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Reverse Working Voltage	V_{RWM}				5.5	V
Breakdown Voltage	V_{BR}	I _T = 1 mA, (Note 1)	5.5	6.5		V
Reverse Leakage Current	I _R	V _{RWM} = 5.5 V			1.0	μΑ
Clamping Voltage	V _C	I _{PP} = 1 A (Note 2)		8.3	10	V
		I _{PP} = 5 A (Note 3)		8.5	9.0	V
		I _{PP} = 8 A (Note 3)		9.2	10	V
ESD Clamping Voltage	V _C	Per IEC61000-4-2 (Note 4)	See Figures 1 & 2			
Maximum Peak Pulse Current	I _{PP}	8/20 μs Waveform (Note 3)			12	Α
Junction Capacitance	CJ	V _R = 0 V, f = 1 MHz between I/O Pins and GND			0.6	pF
		V _R = 0 V, f = 1 MHz between I/O Pins			0.3	pF

- 1. V_{BR} is measured at pulse test current I_T . 2. Nonrepetitive current pulse (I/O to GND).
- 3. Nonrepetitive current pulse (Pin 5 to Pin 2)
- 4. For test procedure see Figures 3 and 4 and Application Note AND8307/D.

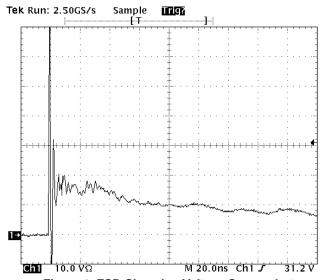


Figure 1. ESD Clamping Voltage Screenshot Positive 8 kV Contact per IEC61000-4-2

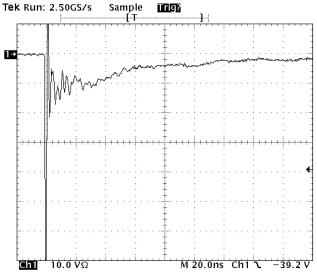


Figure 2. ESD Clamping Voltage Screenshot Negative 8 kV Contact per IEC61000-4-2

IEC 61000-4-2 Spec.

Level	Test Volt- age (kV)	First Peak Current (A)	Current at 30 ns (A)	Current at 60 ns (A)
1	2	7.5	4	2
2	4	15	8	4
3	6	22.5	12	6
4	8	30	16	8

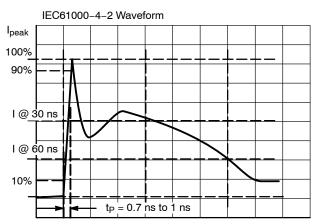


Figure 3. IEC61000-4-2 Spec

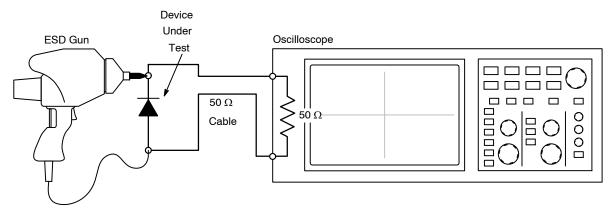


Figure 4. Diagram of ESD Test Setup

The following is taken from Application Note AND8308/D – Interpretation of Datasheet Parameters for ESD Devices.

ESD Voltage Clamping

For sensitive circuit elements it is important to limit the voltage that an IC will be exposed to during an ESD event to as low a voltage as possible. The ESD clamping voltage is the voltage drop across the ESD protection diode during an ESD event per the IEC61000-4-2 waveform. Since the IEC61000-4-2 was written as a pass/fail spec for larger

systems such as cell phones or laptop computers it is not clearly defined in the spec how to specify a clamping voltage at the device level. ON Semiconductor has developed a way to examine the entire voltage waveform across the ESD protection diode over the time domain of an ESD pulse in the form of an oscilloscope screenshot, which can be found on the datasheets for all ESD protection diodes. For more information on how ON Semiconductor creates these screenshots and how to interpret them please refer to AND8307/D.

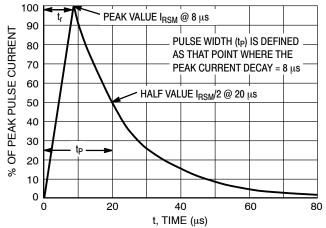


Figure 5. 8/20 µs Pulse Waveform

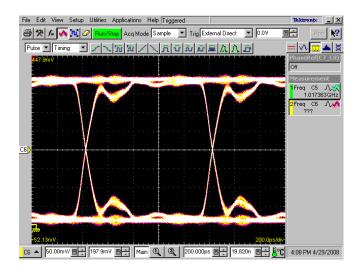


Figure 6. 500 MHz Data Pattern

ORDERING INFORMATION

Device	Marking	Package	Shipping [†]	
NUP4114UCLW1T1G	X2			
NUP4114UCLW1T2G	X2	SC-88	3000 / Tape & Reel	
SZNUP4114UCLW1T2G	X2	(Pb-Free)		
NUP4114UCW1T2G	X4			
NUP4114UPXV6T1G	5.4	SOT-563	4000 / T	
NUP4114UPXV6T2G	P4	(Pb-Free)	4000 / Tape & Reel	
NUP4114HMR6T1G	P4H	TSOP-6	0000/7 0.0	
SZNUP4114HMR6T1G	P4H	(Pb-Free)	3000 / Tape & Reel	

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

APPLICATIONS INFORMATION

The new NUP4114 is a low capacitance ESD diode array designed to protect sensitive electronics such as communications systems, computers, and computer peripherals against damage due to ESD events or transient overvoltage conditions. Because of its low capacitance, it can be used in high speed I/O data lines. The integrated design of the NUP4114 offers low capacitance steering diodes and an ESD diode integrated in a single package (TSOP-6). If a transient condition occurs, the steering diodes will drive the transient to the positive rail of the power supply or to ground. This device protects the power line against overvoltage conditions to avoid damage to the power supply and any downstream components.

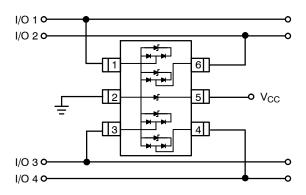
NUP4114 Configuration Options

The NUP4114 is able to protect up to four data lines against transient overvoltage conditions by driving them to a fixed reference point for clamping purposes. The steering diodes will be forward biased whenever the voltage on the protected line exceeds the reference voltage (V_f or V_{CC} + V_f). The diodes will force the transient current to bypass the sensitive circuit.

Data lines are connected at pins 1, 3, 4 and 6. The negative reference is connected at pin 2. This pin must be connected directly to ground by using a ground plane to minimize the PCB's ground inductance. It is very important to reduce the PCB trace lengths as much as possible to minimize parasitic inductances.

Option 1

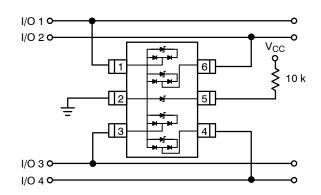
Protection of four data lines and the power supply using V_{CC} as reference.



For this configuration, connect pin 5 directly to the positive supply rail ($V_{\rm CC}$), the data lines are referenced to the supply voltage. The internal ESD diode prevents overvoltage on the supply rail. Biasing of the steering diodes reduces their capacitance.

Option 2

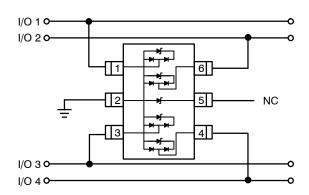
Protection of four data lines with bias and power supply isolation resistor.



The NUP4114 can be isolated from the power supply by connecting a series resistor between pin 5 and V_{CC} . A 10 k Ω resistor is recommended for this application. This will maintain a bias on the internal ESD and steering diodes, reducing their capacitance.

Option 3

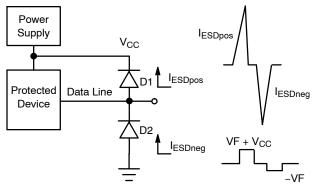
Protection of four data lines using the internal ESD diode as reference.



In applications lacking a positive supply reference or those cases in which a fully isolated power supply is required, the internal ESD can be used as the reference. For these applications, pin 5 is not connected. In this configuration, the steering diodes will conduct whenever the voltage on the protected line exceeds the working voltage of the ESD plus one diode drop ($V_C = V_f + V_{ESD}$).

ESD Protection of Power Supply Lines

When using diodes for data line protection, referencing to a supply rail provides advantages. Biasing the diodes reduces their capacitance and minimizes signal distortion. Implementing this topology with discrete devices does have disadvantages. This configuration is shown below:



Looking at the figure above, it can be seen that when a positive ESD condition occurs, diode D1 will be forward biased while diode D2 will be forward biased when a negative ESD condition occurs. For slower transient conditions, this system may be approximated as follows:

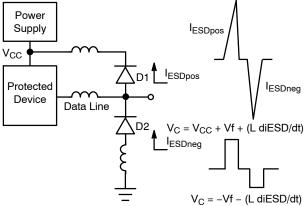
For positive pulse conditions:

$$V_c = V_{CC} + V_{fD1}$$

For negative pulse conditions:

$$V_c = -V_{fD2}$$

ESD events can have rise times on the order of some number of nanoseconds. Under these conditions, the effect of parasitic inductance must be considered. A pictorial representation of this is shown below.



An approximation of the clamping voltage for these fast transients would be:

For positive pulse conditions:

$$V_c = V_{CC} + Vf + (L \text{ diesd/dt})$$

For negative pulse conditions:

$$V_c = -V_f - (L \operatorname{dieso}/\operatorname{dt})$$

As shown in the formulas, the clamping voltage (V_c) not only depends on the Vf of the steering diodes but also on the L diesp/dt factor. A relatively small trace inductance can result in hundreds of volts appearing on the supply rail. This endangers both the power supply and anything attached to that rail. This highlights the importance of good board

layout. Taking care to minimize the effects of parasitic inductance will provide significant benefits in transient immunity.

Even with good board layout, some disadvantages are still present when discrete diodes are used to suppress ESD events across datalines and the supply rail. Discrete diodes with good transient power capability will have larger die and therefore higher capacitance. This capacitance becomes problematic as transmission frequencies increase. Reducing capacitance generally requires reducing die size. These small die will have higher forward voltage characteristics at typical ESD transient current levels. This voltage combined with the smaller die can result in device failure.

The ON Semiconductor NUP4114 was developed to overcome the disadvantages encountered when using discrete diodes for ESD protection. This device integrates an ESD diode within a network of steering diodes.

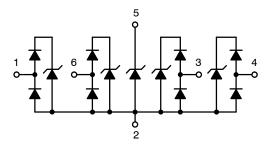
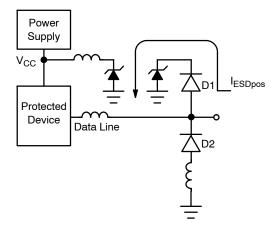


Figure 7. NUP4114 Equivalent Circuit

During an ESD condition, the ESD current will be driven to ground through the ESD diode as shown below.



The resulting clamping voltage on the protected IC will be:

$$V_c = V_F + V_{ESD}$$
.

The clamping voltage of the ESD diode depends on the magnitude of the ESD current. The steering diodes are fast switching devices with unique forward voltage and low capacitance characteristics.



TSOP-6 CASE 318G-02 **ISSUE V**

12

C SEATING PLANE

DATE 12 JUN 2012

STYLE 6: PIN 1. COLLECTOR 2. COLLECTOR

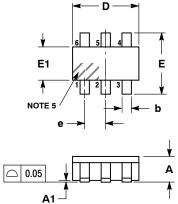
3. BASE 4. EMITTER 5. COLLECTOR 6. COLLECTOR

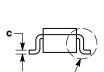
STYLE 12:

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 2. CONTROLLING DIMENSION: MILLIMETERS.
 3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH. MINIMUM
- MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL. DIMENSIONS D AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.15 PER SIDE. DIMENSIONS D
- AND E1 ARE DETERMINED AT DATUM H.
 PIN ONE INDICATOR MUST BE LOCATED IN THE INDICATED ZONE.

	MILLIMETERS				
DIM	MIN	NOM	MAX		
Α	0.90	1.00	1.10		
A1	0.01	0.06	0.10		
b	0.25	0.38	0.50		
С	0.10	0.18	0.26		
D	2.90	3.00	3.10		
E	2.50	2.75	3.00		
E1	1.30	1.50	1.70		
е	0.85	0.95	1.05		
L	0.20	0.40	0.60		
L2	0.25 BSC				
N.A	00		4.00		





DETAIL Z

DETAIL Z

Н

A1	<u> </u>	▼
STYLE 1: PIN 1. DRAIN 2. DRAIN 3. GATE 4. SOURCE 5. DRAIN 6. DRAIN	STYLE 2: PIN 1. EMITTER 2 2. BASE 1 3. COLLECTOR 1 4. EMITTER 1 5. BASE 2 6. COLLECTOR 2	STYLE 3: PIN 1. E 2. N 3. F 4. V 5. V

3. GATE 4. SOURCE 5. DRAIN 6. DRAIN	3. COLLECTOR 1 4. EMITTER 1 5. BASE 2 6. COLLECTOR 2
STYLE 7:	STYLE 8:
PIN 1. COLLECTOR	PIN 1. Vbus
2. COLLECTOR	2. D(in)

3. BASE 4. N/C

STYLE 13: PIN 1. GATE 1

6. EMITTER

2. SOURCE 2

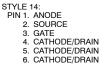
3. GATE 2

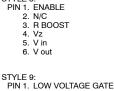
4. DRAIN 2

5. SOURCE 1

DRAIN 1







2. DRAIN

4. DRAIN

STYL PIN

	HIGH VOLTAGE
E ·	15: ANODE
	SOURCE
3.	GATE
4.	DRAIN

.E 15:	STYLE 16:
 ANODE 	PIN 1. ANODE/CATHODE
2. SOURCE	2. BASE
3. GATE	EMITTER
4. DRAIN	COLLECTOR
5. N/C	5. ANODE
CATHODE	6. CATHODE

GATE

STYLE 4: PIN 1. N/C 2. V in	
NOT U	
4. GROUI	
ENABL	E.
6. LOAD	

2. GND

5. VBUS 6. D(IN)+

3. D(OUT)-4. D(IN)-

STYLE 10:

3. COLLECTOR 1 4. EMITTER 1 BASE 1 STYLE 11: PIN 1. D(OUT)+

STYLE 5:

PIN 1. EMITTER 2 2. BASE 2

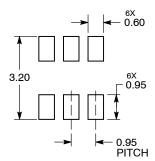
6. COLLECTOR 2 PIN 1. SOURCE 1 2. DRAIN 2



3 ANODE/CATHODE CATHODE

COLLECTOR

RECOMMENDED **SOLDERING FOOTPRINT***



DIMENSIONS: MILLIMETERS

TSOP-6

GENERIC MARKING DIAGRAM*





XXX = Specific Device Code Α =Assembly Location

", may or may not be present.

Υ = Year

W = Work Week = Pb-Free Package XXX = Specific Device Code M = Date Code

= Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "

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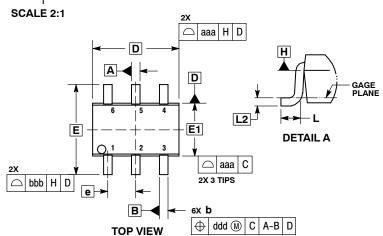
DESCRIPTION:

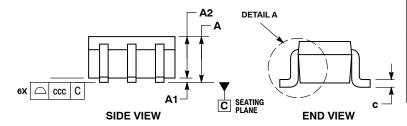
PAGE 1 OF 1

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

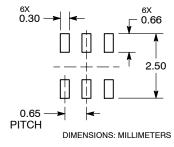
SC-88/SC70-6/SOT-363 CASE 419B-02 **ISSUE Y**

DATE 11 DEC 2012





RECOMMENDED SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

NOTES:

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 CONTROLLING DIMENSION: MILLIMETERS
- CONTROLLING DIMENSION: MILLIMETERS.
 DIMENSIONS D AND E1 DO NOT INCLUDE MOLD FLASH,
- DIMENSIONS D AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.20 PER END. DIMENSIONS D AND E1 AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY AND DATUM H. DATUMS A AND B ARE DETERMINED AT DATUM H. DIMENSIONS b AND c APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.08 AND 0.15 FROM THE TIP.

- DIMENSION 6 DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 TOTAL IN EXCESS OF DIMENSION 6 AT MAXIMUM MATERIAL CONDITION. THE DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OF THE FOOT.

	MILLIMETERS INCHES				3	
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α			1.10			0.043
A1	0.00		0.10	0.000		0.004
A2	0.70	0.90	1.00	0.027	0.035	0.039
b	0.15	0.20	0.25	0.006	0.008	0.010
С	0.08	0.15	0.22	0.003	0.006	0.009
D	1.80	2.00	2.20	0.070	0.078	0.086
Е	2.00	2.10	2.20	0.078	0.082	0.086
E1	1.15	1.25	1.35	0.045	0.049	0.053
е	0.65 BSC			0	.026 BS	С
L	0.26	0.36	0.46	0.010	0.014	0.018
L2		0.15 BS	C	(0.006 BS	SC
aaa	0.15				0.006	
bbb	0.30				0.012	
ccc	0.10				0.004	
ddd		0.10			0.004	

GENERIC MARKING DIAGRAM*



XXX = Specific Device Code

= Date Code* = Pb-Free Package

(Note: Microdot may be in either location)

- *Date Code orientation and/or position may vary depending upon manufacturing location.
- *This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

STYLES ON PAGE 2

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DESCRIPTION:	SC-88/SC70-6/SOT-363		PAGE 1 OF 2	

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SC-88/SC70-6/SOT-363 CASE 419B-02 ISSUE Y

DATE 11 DEC 2012

STYLE 1: PIN 1. EMITTER 2 2. BASE 2 3. COLLECTOR 1 4. EMITTER 1 5. BASE 1 6. COLLECTOR 2	STYLE 2: CANCELLED	STYLE 3: CANCELLED	STYLE 4: PIN 1. CATHODE 2. CATHODE 3. COLLECTOR 4. EMITTER 5. BASE 6. ANODE	STYLE 5: PIN 1. ANODE 2. ANODE 3. COLLECTOR 4. EMITTER 5. BASE 6. CATHODE	STYLE 6: PIN 1. ANODE 2 2. N/C 3. CATHODE 1 4. ANODE 1 5. N/C 6. CATHODE 2
STYLE 7: PIN 1. SOURCE 2 2. DRAIN 2 3. GATE 1 4. SOURCE 1 5. DRAIN 1 6. GATE 2	STYLE 8: CANCELLED	STYLE 9: PIN 1. EMITTER 2 2. EMITTER 1 3. COLLECTOR 1 4. BASE 1 5. BASE 2 6. COLLECTOR 2	STYLE 10: PIN 1. SOURCE 2 2. SOURCE 1 3. GATE 1 4. DRAIN 1 5. DRAIN 2 6. GATE 2	STYLE 11: PIN 1. CATHODE 2 2. CATHODE 2 3. ANODE 1 4. CATHODE 1 5. CATHODE 1 6. ANODE 2	STYLE 12: PIN 1. ANODE 2 2. ANODE 2 3. CATHODE 1 4. ANODE 1 5. ANODE 1 6. CATHODE 2
STYLE 13: PIN 1. ANODE 2. N/C 3. COLLECTOR 4. EMITTER 5. BASE 6. CATHODE	STYLE 14: PIN 1. VREF 2. GND 3. GND 4. IOUT 5. VEN 6. VCC	STYLE 15: PIN 1. ANODE 1 2. ANODE 2 3. ANODE 3 4. CATHODE 3 5. CATHODE 2 6. CATHODE 1	STYLE 16: PIN 1. BASE 1 2. EMITTER 2 3. COLLECTOR 2 4. BASE 2 5. EMITTER 1 6. COLLECTOR 1	STYLE 17: PIN 1. BASE 1 2. EMITTER 1 3. COLLECTOR 2 4. BASE 2 5. EMITTER 2 6. COLLECTOR 1	STYLE 18: PIN 1. VIN1 2. VCC 3. VOUT2 4. VIN2 5. GND 6. VOUT1
STYLE 19: PIN 1. I OUT 2. GND 3. GND 4. V CC 5. V EN 6. V REF	STYLE 20: PIN 1. COLLECTOR 2. COLLECTOR 3. BASE 4. EMITTER 5. COLLECTOR 6. COLLECTOR	STYLE 21: PIN 1. ANODE 1 2. N/C 3. ANODE 2 4. CATHODE 2 5. N/C 6. CATHODE 1	STYLE 22: PIN 1. D1 (i) 2. GND 3. D2 (i) 4. D2 (c) 5. VBUS 6. D1 (c)	STYLE 23: PIN 1. Vn 2. CH1 3. Vp 4. N/C 5. CH2 6. N/C	STYLE 24: PIN 1. CATHODE 2. ANODE 3. CATHODE 4. CATHODE 5. CATHODE 6. CATHODE
STYLE 25: PIN 1. BASE 1 2. CATHODE 3. COLLECTOR 2 4. BASE 2 5. EMITTER 6. COLLECTOR 1	STYLE 26: PIN 1. SOURCE 1 2. GATE 1 3. DRAIN 2 4. SOURCE 2 5. GATE 2 6. DRAIN 1	STYLE 27: PIN 1. BASE 2 2. BASE 1 3. COLLECTOR 1 4. EMITTER 1 5. EMITTER 2 6. COLLECTOR 2	STYLE 28: PIN 1. DRAIN 2. DRAIN 3. GATE 4. SOURCE 5. DRAIN 6. DRAIN	STYLE 29: PIN 1. ANODE 2. ANODE 3. COLLECTOR 4. EMITTER 5. BASE/ANODE 6. CATHODE	STYLE 30: PIN 1. SOURCE 1 2. DRAIN 2 3. DRAIN 2 4. SOURCE 2 5. GATE 1 6. DRAIN 1

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MECHANICAL CASE OUTLINE

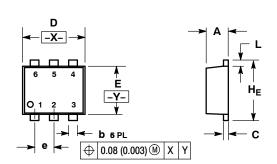
PACKAGE DIMENSIONS





SOT-563, 6 LEAD CASE 463A ISSUE G

DATE 23 SEP 2015



STYLE 1: PIN 1. EMITTER 1 2. BASE 1 3. COLLECTOR 2

4. EMITTER 2 5 BASE 2 6. COLLECTOR 1

STYLE 4: PIN 1. COLLECTOR

 COLLECTOR
 BASE 4. EMITTER 5. COLLECTOR

6. COLLECTOR

STYLE 7: PIN 1. CATHODE 2. ANODE 3. CATHODE

 CATHODE
 ANODE 6. CATHODE

STYLE 10: PIN 1. CATHODE 1

2. N/C 3. CATHODE 2 4. ANODE 2

5 N/C 6. ANODE 1

STYLE 2: PIN 1. EMITTER 1 2. EMITTER2 3. BASE 2

4. COLLECTOR 2 5 BASE 1 6. COLLECTOR 1

STYLE 5:

PIN 1. CATHODE CATHODE
 ANODE

4. ANODE 5. CATHODE 6. CATHODE

STYLE 8: PIN 1. DRAIN 2. DRAIN

3. GATE

4. SOURCE 5. DRAIN 6. DRAIN

STYLE 3: PIN 1. CATHODE 1 2. CATHODE 1 3. ANODE/ANODE 2

4. CATHODE 2 5. CATHODE 2

6. ANODE/ANODE 1

STYLE 6: PIN 1. CATHODE

2. ANODE 3. CATHODE 4. CATHODE 5. CATHODE 6. CATHODE

STYLE 9: PIN 1. SOURCE 1 2. GATE 1

3. DRAIN 2

6. DRAIN 1

4. SOURCE 2 5. GATE 2

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI
- Y14.5M, 1982. CONTROLLING DIMENSION: MILLIMETERS
- MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL.

	MILLIMETERS			INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.50	0.55	0.60	0.020	0.021	0.023
b	0.17	0.22	0.27	0.007	0.009	0.011
С	0.08	0.12	0.18	0.003	0.005	0.007
D	1.50	1.60	1.70	0.059	0.062	0.066
Е	1.10	1.20	1.30	0.043	0.047	0.051
е	0.5 BSC		0.02 BSC			
L	0.10	0.20	0.30	0.004	0.008	0.012
HE	1.50	1.60	1.70	0.059	0.062	0.066

GENERIC MARKING DIAGRAM*



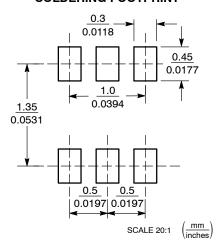
XX = Specific Device Code

= Month Code

= Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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